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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)	Complete if Known	
	Application Number	09/834,751
	Filing Date	April 13, 2001
	First Named Inventor	Velichko, Sergey
	Group Art Unit	2857
	Examiner Name	Miller, Craig
Attorney Docket No: 303.750US1		

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Examiner Initials *	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
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DATE CONSIDERED

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Substitute Disclosure Statement Form (PTO-1449)

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US Patent & Trademark Office, U.S. DEPARTMENT OF COMMERCE

Complete if Known

Application Number	09/834751
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First Named Inventor	Velichko, Sergey
Group Art Unit	2812
Examiner Name	Miller, Craig

Attorney Docket No: 303.750US1

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